



DACO SEMICONDUCTOR CO., LTD.

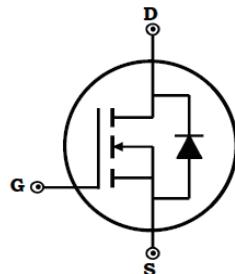
DACMI80N1200

Silicon Carbide Enhancement Mode MOSFET

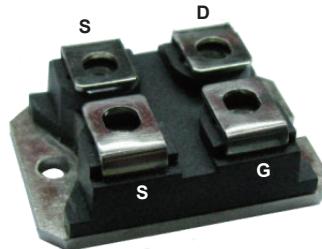
Features

Preliminary

- ◆ $V_{DSS} = 1200V$
- ◆ $R_{DS(ON)} < 34 \text{ m}\Omega @ V_{GS} = 20 \text{ V}$
- ◆ Fully Avalanche Rated
- ◆ Pb Free & RoHS Compliant
- ◆ Isolation Type Package
- ◆ Electrically Isolation base plate



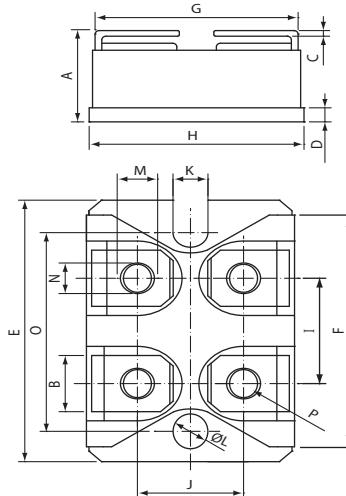
SOT-227



Applications

- ◆ Solar Inverters
- ◆ Switch Mode Power Supplies
- ◆ Power Converters
- ◆ Battery Chargers
- ◆ Motor Drive

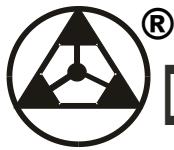
Dimensions in inches and (millimeters)



Absolute Maximum Ratings ($T_c=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	1200	V
Gate-Source Voltage	V_{GS}	-10/+20	V
Drain Current-Continuous @ $T_c = 25^\circ\text{C}$ @ $T_c = 100^\circ\text{C}$	I_D	80 50	A
Drain Current-Pulsed @ $T_c = 25^\circ\text{C}$ ^{Note1}	I_{DM}	250	A
Maximum Power Dissipation	P_D	460	W
Storage Temperature Range	T_{STG}	-50 to +150	°C
Operating Junction Temperature Range	T_J	-50 to +150	°C
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.26	°C/W
Isolation Voltage (A.C. 1 minute)	V_{iso}	4000	V
Mounting torque (M5 Screw)	M_d	3-5	N _m

DIM	INCHES		MM	
	MIN	MXA	MIN	MXA
A	.500	.519	12.70	13.60
B	.307	.322	7.80	8.20
C	.029	.033	.75	.84
D	.077	.082	1.95	2.10
E	1.487	1.502	37.80	38.20
F	1.250	1.258	31.75	32.00
G	.931	.956	23.65	24.30
H	.996	1.007	25.30	25.60
I	.586	.594	14.90	15.10
J	.492	.516	12.50	13.10
K	.161	.169	4.10	4.30
L	.161	.169	4.10	4.30
M	.181	.191	4.60	4.95
N	.165	.177	4.20	4.50
O	1.184	1.192	30.10	30.30
P			M4*8	



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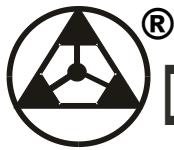
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Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit	
OFF Characteristics							
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}$, $I_{\text{DS}}=0.3\text{mA}$	1200	-	-	V	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=1200\text{V}$	-	-	50	μA	
Gate-Body Leakage	I_{GSS}	$V_{\text{GS}}=20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	500	nA	
ON Characteristics							
Gate Threshold Voltage	V_{TH}	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{DS}}=8\text{mA}$	2.0	2.5	3.5	V	
Drain-Source On-State Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}}=20\text{V}$, $I_{\text{DS}}=80\text{A}$	-	28	34	$\text{m}\Omega$	
Gate Resistance	R_{G}		-	1.6	2.9	Ω	
Forward Transconductance	g_{fs}	$ V_{\text{DS}} > 2 I_{\text{D}} R_{\text{DS}(\text{on})M}$, $I_{\text{D}} = 50\text{A}$	Note ¹	-	21	-	S
Dynamic Characteristics							
Input Capacitance	C_{iss}	$V_{\text{DS}}=1000\text{V}$ $V_{\text{GS}}=0\text{V}$ Freq.=1MHz	-	3050	-	pF	
Output Capacitance	C_{oss}		-	184	-		
Reverse Transfer Capacitance	C_{rss}		-	40	-		
Turn-On Switching Energy	E_{on}	$V_{\text{DD}}=800\text{V}$, $V_{\text{GS}}=-5\text{V}/+20\text{V}$ $I_{\text{D}} = 50\text{A}$, $R_{\text{G(ext)}} = 6.8\Omega$ Load=412 μH	-	1.4	-	mJ	
Turn-Off Switching Energy	E_{off}		-	0.3	-		
Switching Characteristics							
Turn-On Delay Time	$t_{\text{d(on)}}$	$V_{\text{DD}}=800\text{V}$ $V_{\text{GS}}=20\text{V}$ $I_{\text{DS}}=50\text{A}$ $R_{\text{G}}=2.5\Omega$	-	16	-	ns	
Rise Time	t_r		-	29	-		
Turn-Off Delay Time	$t_{\text{d(off)}}$		-	32	-		
Fall Time	t_f		-	30	-		
Total Gate Charge at 10V	Q_g	$V_{\text{DS}}=800\text{V}$ $V_{\text{GS}}=20\text{V}$ $I_{\text{DS}}=50\text{A}$	-	196	-	nC	
Gate to Source Charge	Q_{gs}		-	24	-		
Gate to Drain Charge	Q_{gd}		-	48	-		
Reverse Diode Characteristics							
Drain-Source Diode Forward Voltage	V_F	$T_J = 25^\circ\text{C}$, $I_F = 80\text{A}$	-	-	6.5	V	
Diode Continuous Forward Current	I_F		-	-	50	A	
Diode Pulsed Current ^{Note 1}	$I_{F,\text{pulse}}$		-	-	250	A	
Reverse Recovery time	T_{RR}	$I_F = 0.5\text{V}$, $I_R = 1.0\text{A}$, $I_{\text{RR}} = 0.25\text{A}$	-	-	100	ns	

Notes:

1. Pulse Test: Pulse Width $\leq 300 \mu\text{s}$, Duty Cycle $> 2\%$.



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Typical Characteristics

Figure 1. Maximum Power Dissipation (MOSFET) Derating vs. Case Temperature

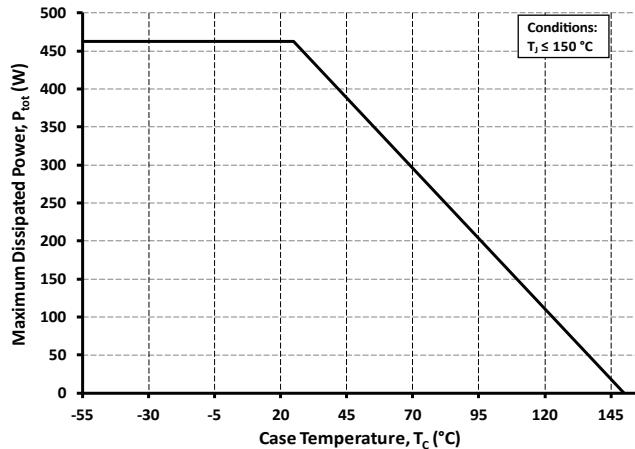


Figure 3. Safe Operating Area(MOSFET)

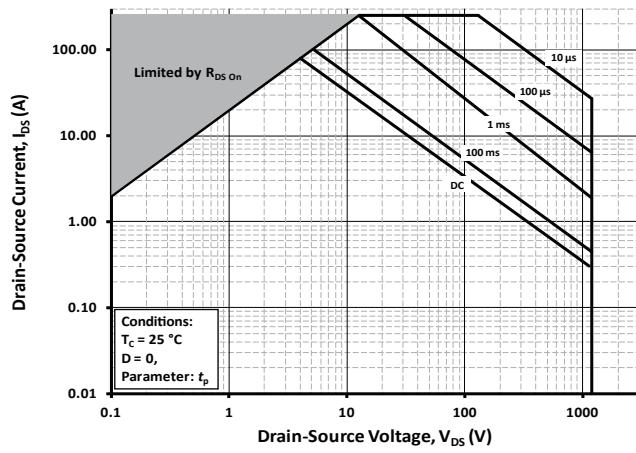


Figure 5. Output Characteristics $T_j = 25^\circ\text{C}$

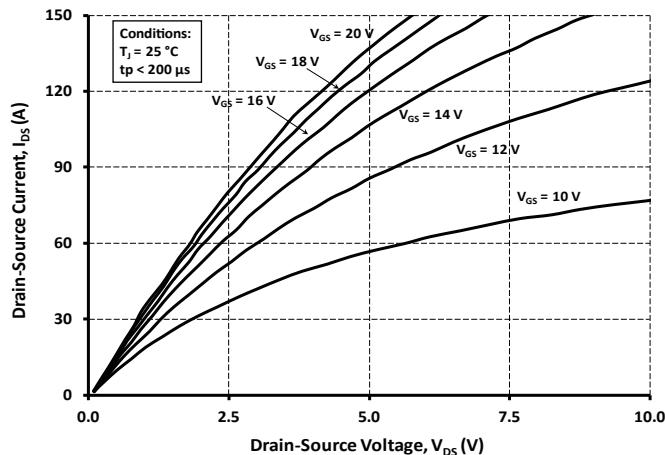


Figure 2. Continuous Drain Current (MOSFET) Derating vs Case Temperature

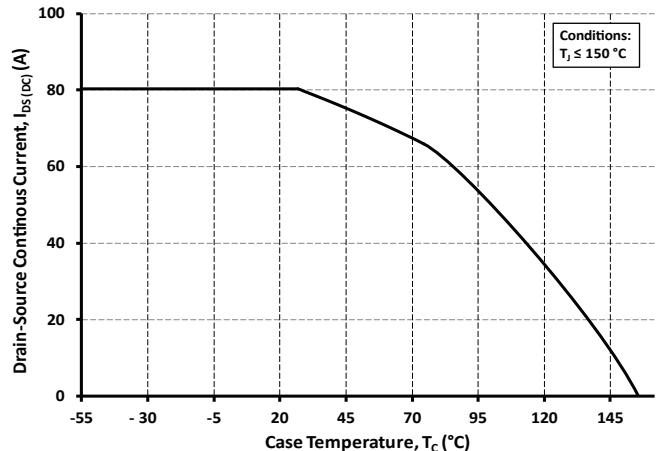


Figure 4. MOSFET Junction to Case Thermal Impedance

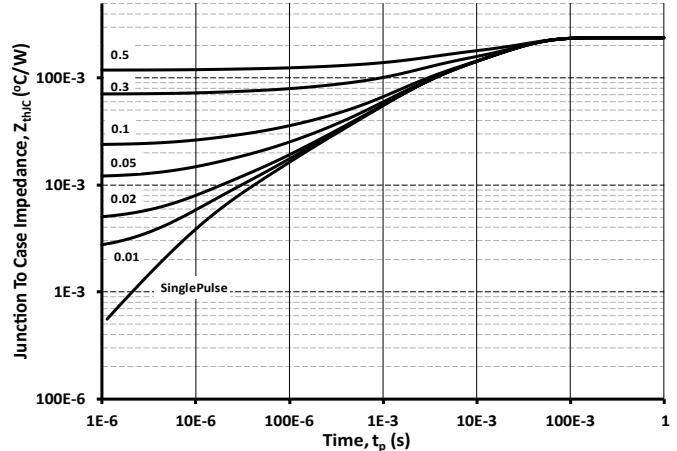
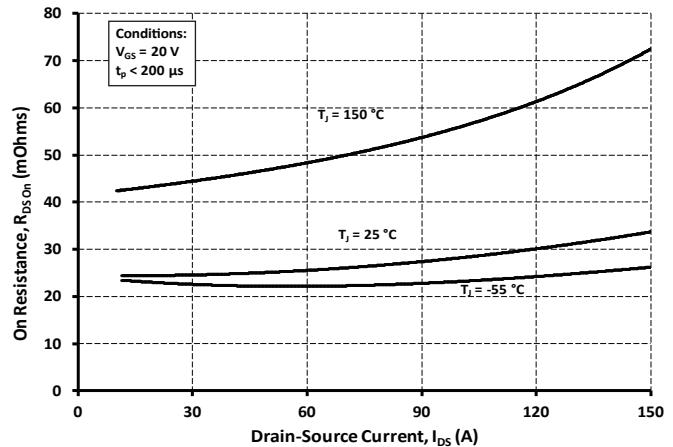


Figure 6. On-Resistance vs. Drain Current For Various Temperatures





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Figure 7. On-Resistance vs. Temperature For Various Gate-Source Voltage

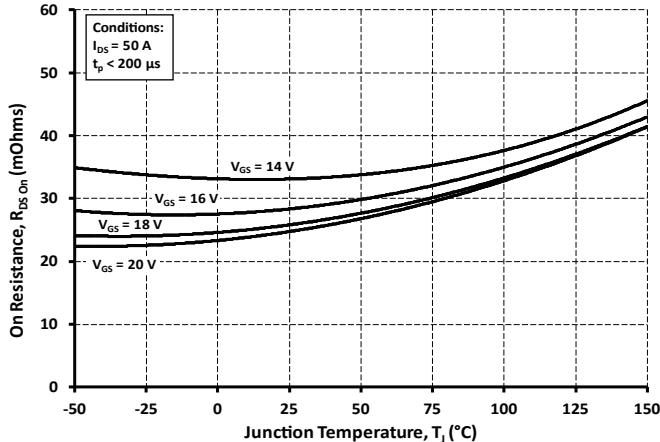


Figure 8. Threshold Voltage vs. Temperature

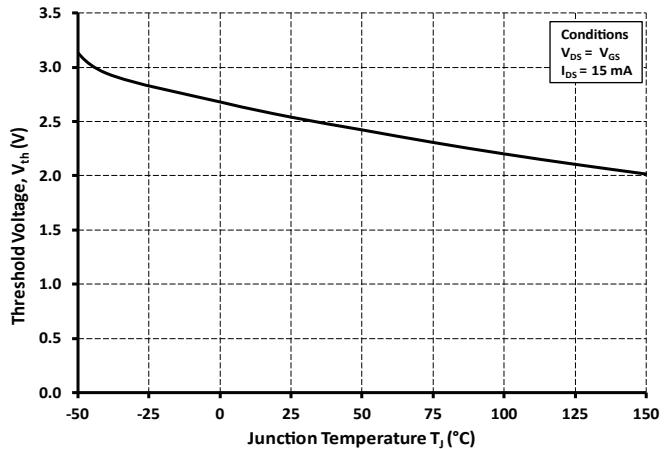


Figure 9. Transfer Characteristic for Various Junction Temperatures

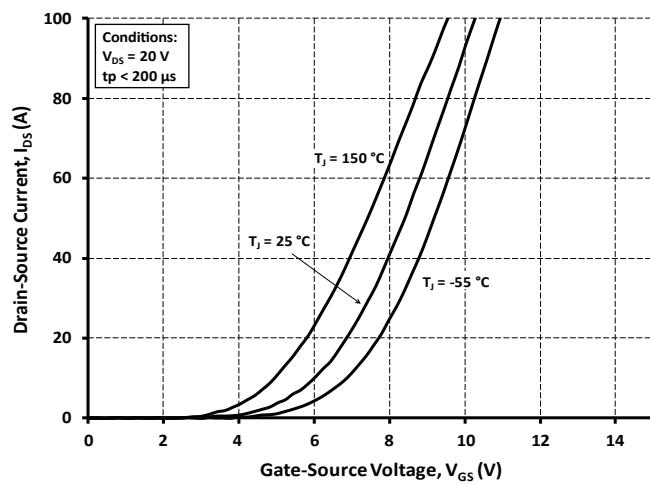


Figure 10. Capacitances vs. Drain-Source Voltage (0 - 1 kV)

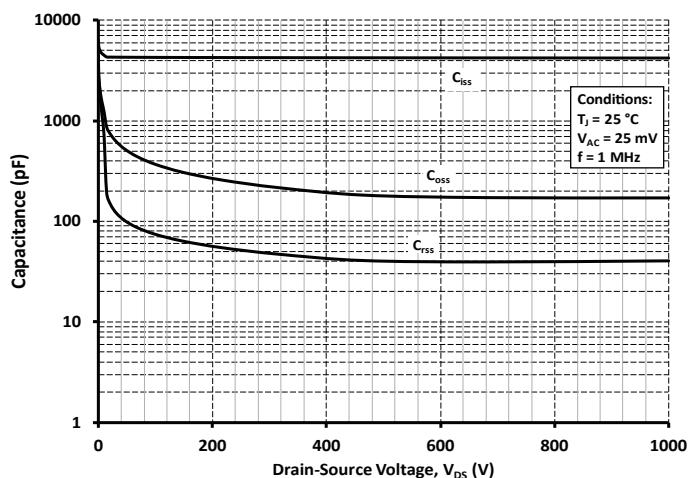


Figure 11. Typical forward characteristics of reverse diode

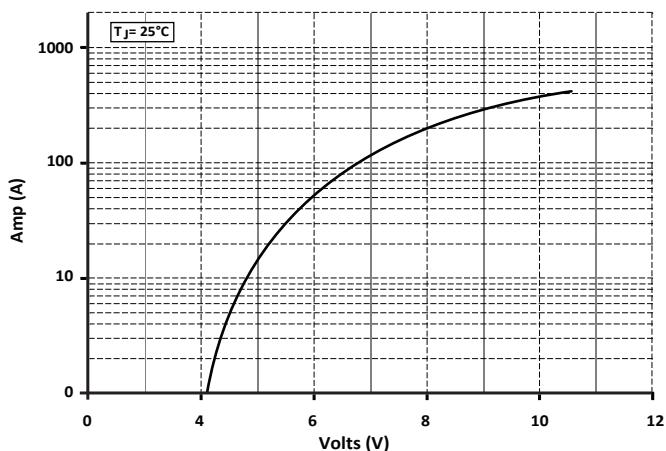
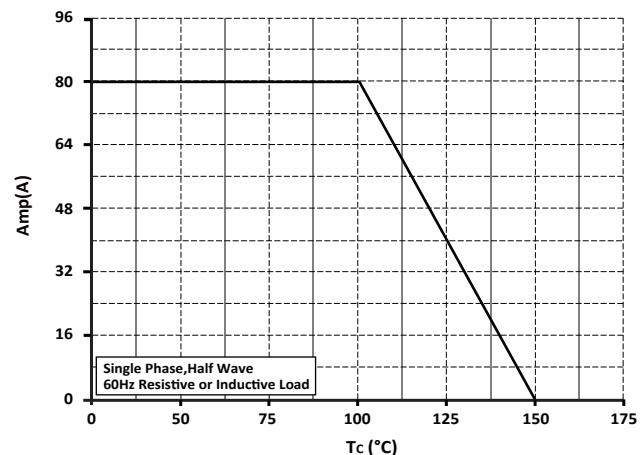


Figure 12. Forward derating curve of reverse diode





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Figure 13. Peak forward surge current of reverse diode

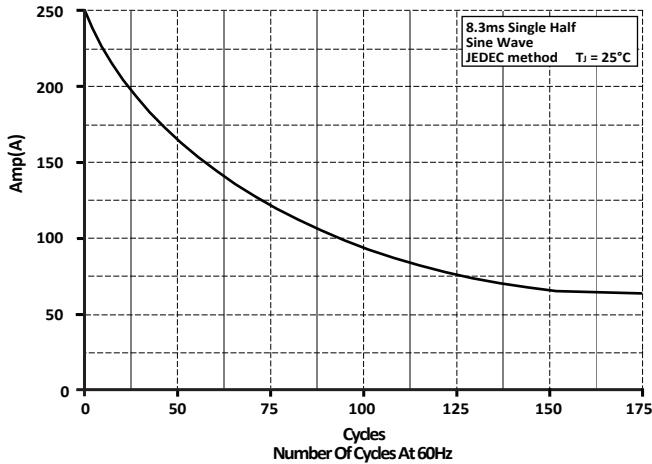


Figure 14. Typical reverse diode characteristics

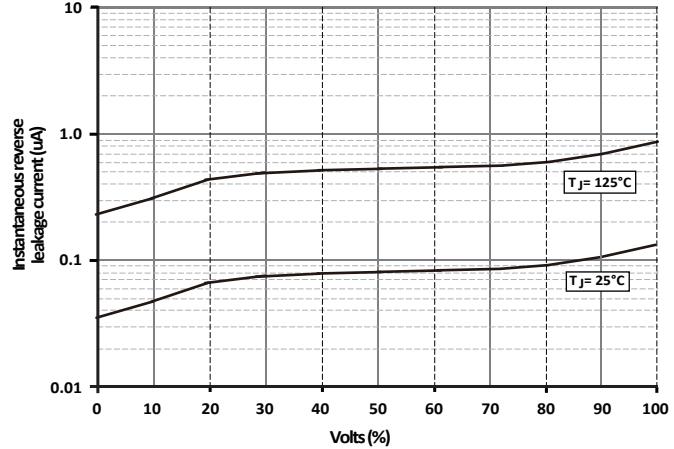


Figure 15. Gate Charge Characteristics

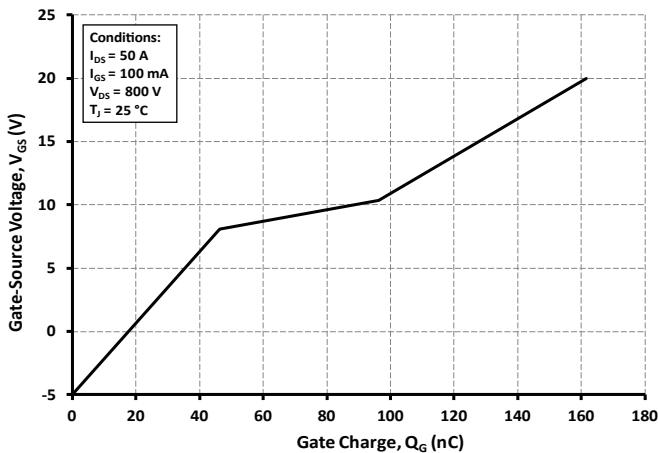


Figure 16. Inductive Switching Energy vs. Temperature

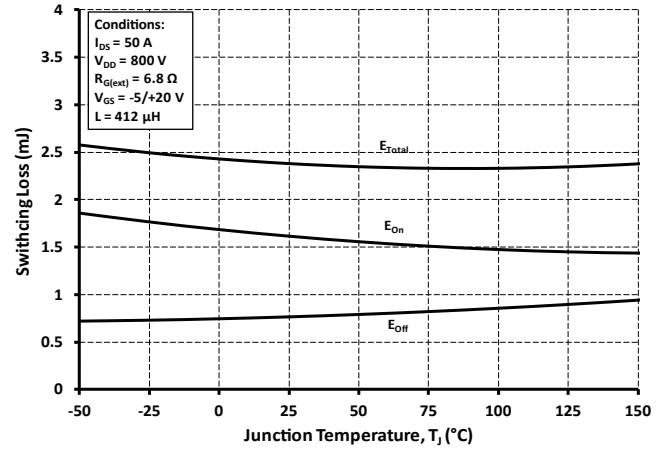


Figure 17. Timing vs. $R_{G(\text{ext})}$

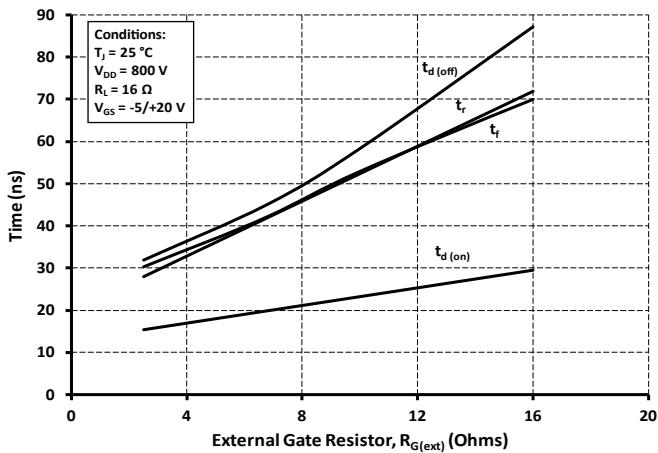
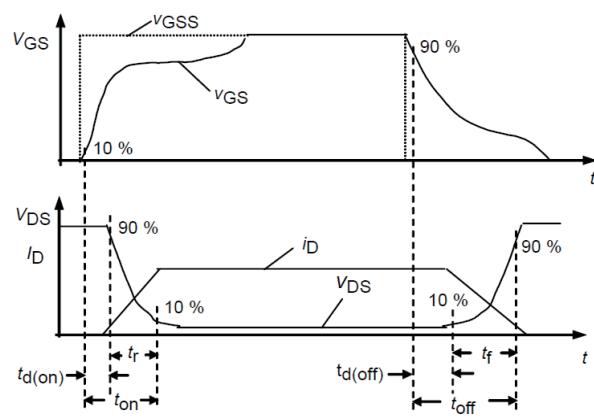


Figure 18. Resistive Switching Time Description



IEC 1161/04